Alternative graphs as a mathematical tool and knowledge representation for diagnosis purposes in digital systems
Ubar, Raimund-Johannes BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 285-292: ill

An ontology-based intelligent learning object for teaching the basics of digital logic
Robal, Tarmo; **Kann, Taavi**; **Kalja, Ahto** 2011 IEEE International Conference on Microelectronic Systems Education (MSE) : 5-6 June 2011, San Diego, CA, USA 2011 / p. 106-107

Application of structurally synthesized binary decision diagrams for timing simulation of digital circuits
Jutman, Artur; **Ubar, Raimund-Johannes** Proceedings of the Estonian Academy of Sciences. Engineering 2001 / 4, p. 269-288 : ill

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
Rang, Toomas; **Min, Mart**; **Ubar, Raimund-Johannes** 1994

BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia)
1994 https://www.ester.ee/record=b2150914*est

BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia
2002 http://www.ester.ee/record=b2150914*est

BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia
2004 https://www.ester.ee/record=b1982896*est

BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia
2004 http://www.ester.ee/record=b2150914*est

BEC 2006 : 2006 International Baltic Electronics Conference : Tallinn University of Technology, October 2-4, 2006, Tallinn, Estonia : proceedings of the 10th Biennial Baltic Electronics Conference
2006 http://www.ester.ee/record=b2150914*est

BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia
2008 http://www.ester.ee/record=b2150914*est

BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 4-6, 2010, Tallinn, Estonia
2010 http://www.ester.ee/record=b2150914*est

BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia
2012 http://www.ester.ee/record=b2150914*est

BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia
2014 http://www.ester.ee/record=b2150914*est

BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia
2016 http://www.ester.ee/record=b2150914*est

BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings
Rang, Toomas; **Min, Mart**; **Ubar, Raimund-Johannes** 1996 https://www.ester.ee/record=b2150914*est

BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings
1998 https://www.ester.ee/record=b2150914*est

A BIST scheme for testing mixed analogue and digital circuits
Robson, Malcolm; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 183-186: ill

Calculation of testability measures on structurally synthesized binary decision diagrams
Ubar, Raimund-Johannes; **Heinlaid, J.**; **Raik, Jaan**; Raun, L. BEC'98 : the 6th Biennial Conference on Electronics and

Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 179-182: ill

Calculation of the diagnosibility of digital circuits without using fault models
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Raik, Jaan** BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 159-162 : ill

Case study in testing digital systems
Ubar, Raimund-Johannes Baltic electronics 1995 / 1, p. 24-27

A CMOS quadrature baseband frequency synthesizer/modulator
Kosunen, Marko; Vankka, Jouko; Waltari, Mikko; Sumanen, Lauri; Koli, Kimmo; Halonen, Kari BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 219-222: ill

Collaborative distributed computing in the field of digital electronics testing
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** Balanced Automation Systems for Future Manufacturing Networks : 9th IFIP WG 5.5 International Conference : BASYS 2010 : Valencia, Spain, July 21-23, 2010 : proceedings 2010 / p. 145-152

Collaborative distributed fault simulation for digital electronic circuits
Ivask, Eero; **Devadze, Sergei**; **Ubar, Raimund-Johannes** Intelligent Distributed Computing IV : proceedings of the 4th International Symposium on Intelligent Distributed Computing - IDC 2010 : Tangier, Morocco, September 2010 2010 / p. 67-76

Defect-oriented modul-level fault diagnosis in digital circuits
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan** Proceedings of the 2011 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 13-15, 2011, Gottbus, Germany 2011 / p. 81-86

Digitaalelektroonika : laboratoorsete tööde kogumik
1994 http://www.ester.ee/record=b1065462*est

Digitaalelektroonika alused : skeemid : abimaterjal loengute jälgimise ja konspekteerimise hõlbustamiseks
1994 https://www.ester.ee/record=b1065765*est

Digitaali disain - ideest realisatsioonini
Ellervee, Peeter A & A 2008 / lk. 6-10 : ill https://artiklid.elnet.ee/record=b1021438*est

Digitaalsüsteemide diagnostika
Ubar, Raimund-Johannes 2005 http://www.ester.ee/record=b2097071*est

Digitaalsüsteemide diagnostika Tallinna Tehnikaülikoolis
Ubar, Raimund-Johannes Teadusmõte Eestis : tehnikateadused 2002 / lk. 107-113 : ill

Digital test in WEB-based environment
Ivask, Eero 2006 https://www.ester.ee/record=b2158119*est

Distributed approach for genetic test generation in the field of digital electronics
Ivask, Eero; **Raik, Jaan**; **Ubar, Raimund-Johannes** Intelligent Distributed Computing, Systems and Applications : proceedings of the 2nd International Symposium on Intelligent Distributed Computing : IDC 2008 : Catania, Italy, 2008 2008 / p. 127-136

Dynamic analysis of digital circuits with 5-valued simulation
Ubar, Raimund-Johannes Mixed design of integrated circuits and systems 1998 / p. 187-192: ill
https://link.springer.com/chapter/10.1007/978-1-4615-5651-0_29

Effective self adaptive multiple source localization technique by primal dual interior point method in binary sensor networks
Khan, Muhidul Islam; Xia, Kewen IEEE communications letters 2017 / p. 1119-1122 : ill https://doi.org/10.1109/LCOMM.2017.2657508

E-learning environment in the area of digital microelectronics
Jutman, Artur; **Sudnitsõn, Aleksander**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich ITHET 2004 : proceedings of the Fifth International Conference on Information Technology based Higher Education and Training : 31 May - 2 June, 2004, Istanbul, Turkey 2004 / p. 278-283 : ill

E-learning of digital logic
Robal, Tarmo; **Brik, Marina**; **Aarna, Margit** EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 120-123 : ill

E-learning tools for teaching self-test of digital electronics
Jutman, Artur; Gramatova, Elena; Pikula, T.; **Ubar, Raimund-Johannes** 15 EAEEIE International Conference on Innovation in Education for Electrical and Information Engineering : Sofia, Bulgaria, May 27-29, 2004 2004 / p. 267-272 : ill

E-learning tools for teaching the decomposition based digital synthesis
Sudnitsõn, Aleksander; **Kruus, Margus** EWME 2006 proceedings : 6th International Workshop on Microelectronics Education : 8-9 June, 2006, Stockholm, Sweden 2006 / p. 63-66 https://pld.ttu.ee/~kruus/EWME_06_sudn.pdf

Fault collapsing in digital circuits using fast fault dominance and equivalence analysis with SSBDDs
Ubar, Raimund-Johannes; **Jürimägi, Lembit**; **Orasson, Elmet**; **Raik, Jaan** VLSI-SoC : Design for Reliability, Security, and Low Power : 23rd IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2015 Daejeon, Korea, October 5-7, 2015 : revised selected papers 2016 / p. 23-45 : ill https://doi.org/10.1007/978-3-319-46097-0_2 Conference Proceedings at Scopus Article at Scopus Article at WOS

FPGA platform based digital design education
Mihhailov, Dmitri; **Kruus, Margus**; **Sudnitsõn, Aleksander** Proceedings of the 9th International Conference on Computer Systems and Technologies and Workshop for PhD Students in Computing : CompSysTech'2008. Vol. 374, ACM International Conference Proceeding Series 2008 / p. IV.4-1 - IV.4-6 : ill https://dl.acm.org/doi/pdf/10.1145/1500879.1500938

FSM decomposition with application to FPGA synthesis
Sudnitsõn, Aleksander; **Mihhailov, Dmitri**; **Kruus, Margus**; Tarletski, Konstantin International Conference on Computer Systems and Technologies - CompSysTech'09 : Ruse, Bulgaria 2009 / p. IV.4.1-IV.4.6 https://dl.acm.org/doi/10.1145/1731740.1731820

Functional level testability analysis for digital circuits
Ubar, Raimund-Johannes; Kuchcinski, Ktzysztof ETC '93 : European Test Conference, Rotterdam, The Netherlands, April 19-22, 1993 1993 / p. 545-546

Hierarchical physical defect reasoning in digital circuits
Kostin, Sergei; **Ubar, Raimund-Johannes**; **Raik, Jaan**; **Brik, Marina** Estonian journal of engineering 2011 / 3, p. 185-200

Hybrid BIST optimization using reseeding and test set compaction
Jervan, Gert; **Orasson, Elmet**; **Kruus, Helena**; **Ubar, Raimund-Johannes** 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 596-603 : ill http://dx.doi.org/10.1109/DSD.2007.4341529

Hybrid built-in self-test and test generation techniques for digital systems
Jervan, Gert 2005 https://www.ester.ee/record=b2177537*est

Investigating defects in digital circuits by Boolean differential equations
Kruus, Helena; **Orasson, Elmet**; **Robal, Tarmo**; **Ubar, Raimund-Johannes** The 4th International Conference "Distance Learning - Educational Sphere of XXI Century" (DLESC'04) 2004 / p. 432-435

Investigation and development of test generation methods for control part of digital systems
Brik, Marina 2002 http://www.ester.ee/record=b1688656*est

Methods for improving the accuracy and efficiency of fault simulation in digital systems = Meetodid digitaalsüsteemide rikete simuleerimise täpsuse ja efektiivsuse tõstmiseks
Kõusaar, Jaak 2019 https://digi.lib.ttu.ee/i/?11667

Mikroprotsessortehnika
Lehtla, Tõnu; **Kulmar, Lembit** 1995 https://www.ester.ee/record=b1054894*est

Module level defect simulation in digital circuits
Kuzmicz, Wieslaw; Pleskacz, Witold A.; **Raik, Jaan**; **Ubar, Raimund-Johannes** Proceedings of the Estonian Academy of Sciences. Engineering 2001 / 4, p. 253-268

Multi-valued simulation of digital circuits with structurally synthesized binary decision diagrams
Ubar, Raimund-Johannes Multiple valued logic. Vol. 4 1998 / p. 141-157

Overview of digital twin platforms for EV applications
Mohamed, Mahmoud Ibrahim Hassanin; **Rjabtšikov, Viktor**; **Zequera, Rolando Antonio Gilbert** Sensors 2023 / art. 1414, 15 p. : ill https://doi.org/10.3390/s23031414 Journal metrics at Scopus Article at Scopus Journal metrics at WOS Article at WOS

Research environment for teaching digital test
Ivask, Eero; **Jutman, Artur**; **Orasson, Elmet**; **Raik, Jaan**; **Ubar, Raimund-Johannes**; Wuttke, Heinz-Dietrich Synergies between

Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 468-473 : ill https://pld.ttu.ee/dildis/publications/IWK'2004_res_inv.pdf

Selected issues of modeling, verification and testing of digital systems
Jutman, Artur 2004 https://www.ester.ee/record=b1989760*est

Silmade asemel, ehk, Lihtne digitaalne ostsilloskoop arvutile
Sinivee, Veljo Arvutikasutaja 2005 / 2, lk. 10-12 : ill https://artiklid.elnet.ee/record=b1050354*est

Simulation-based verification with APRICOT framework using high-level decision diagrams
Jenihhin, Maksim; **Raik, Jaan**; **Tšepurov, Anton**; **Ubar, Raimund-Johannes** East-West Design & Test Symposium : Moscow, September 18-21, 2009 2009 / p. 13-16 : ill

Sissejuhatus digitaaltehnikasse
Lehtla, Madis 2016 http://www.ester.ee/record=b4618200*est

Test cover calculation in digital systems with word-level decision diagrams
Ubar, Raimund-Johannes; **Raik, Jaan**; **Ivask, Eero**; **Brik, Marina** Вестник Томского государственного университета 2002 / с. 315-319 : ил

Testentwurf für digitale Geräte mit Hilfe der Alternativgraphen
Voolaine, Andrus; Pall, Martin; **Plakk, Mari** Fehler in Automaten 1989 / S. 31-44 : Ill

The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings
2000 https://www.ester.ee/record=b2150914*est

A tool for teaching hierarchical fault diagnosis in digital circuits
Ubar, Raimund-Johannes; **Kostin, Sergei**; **Orasson, Elmet**; **Evartson, Teet**; **Brik, Marina** Proceedings of 9th European Workshop on Microelectronics Education – EWME’12 : Grenoble, France, May 9-11, 2012 2012 / p. 1-4

Trabajadores de la economía gig en la Unión Europea : hacia un cambio en su clasificación jurídica
Kerikmäe, Tanel; **Kajander, Aleksi Oskar Johannes** Revista CIDOB d'afers internacionals 2022 / p. 117-139
https://doi.org/10.24241/rcai.2022.131.2.117

Turbo Tester : a low cost PC-based CAD system for training digital test
Ubar, Raimund-Johannes SampTA'95 : 1995 Workshop on Sampling Theory & Applications, Jurmala, Latvia, September 20-22, 1995 1995

Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaalajas
Shirokova, Veroonika toostusuudised.ee 2022 Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaalajas

Tööstuses toimuvaid protsesse saab nüüdsest jälgida reaalajas
Shirokova, Veroonika Mente et Manu 2022 / lk. 43 https://www.ester.ee/record=b1242496*est

Анализ полноты тестов для цифровых схем на модели альтернативных графов
Kitsnik, Peeter Синтез и диагностика цифровых устройств и систем 1982 / с. 39-51 : илл https://www.ester.ee/record=b1328194*est
https://digikogu.taltech.ee/et/Item/febd586e-d7fa-4fbd-bf41-40576a75f94b